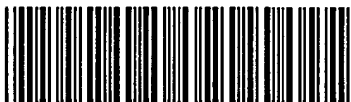


Search Notes

Application/Control No.

10/632,552

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

KARNEZOS, MARCOS

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	678 & 685	3/28/2005	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; EPO; JPO; DERWENT; and IBM_TDB;	3/28/2005	C.C.